



---

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16773**

Generic Copy

---

**Issue Date:** 30-Nov-2011

**TITLE:** VHVIC Second Source Qualification to Gresham Fab

**PROPOSED FIRST SHIP DATE:** 02-Apr-2012

**AFFECTED CHANGE CATEGORY(S):** Wafer Fab Location

**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor Sales Office or Rob Prestoza <[Rob.Prestoza@onsemi.com](mailto:Rob.Prestoza@onsemi.com)>

**SAMPLES:** Contact your local ON Semiconductor Sales Office

**ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Ken Fergus <[Ken.Fergus@onsemi.com](mailto:Ken.Fergus@onsemi.com)>

**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <[quality@onsemi.com](mailto:quality@onsemi.com)>.

**DESCRIPTION AND PURPOSE:**

The purpose of this Final PCN is to notify customers of the Qualification to transfer the devices listed in the FPCN at ON Semiconductor's Wafer Fabrication facilities in Gresham, Oregon.

This qualification is being made to increase the capacity for these devices. This technology is currently produced out of ON Semiconductor's Wafer Fabrication facilities in Aizu, Japan.

These devices are being duplicated at the Gresham Wafer Fab. No die design changes have occurred. No changes to the device performance, Datasheet or Packaging have been made.



**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16773**

**RELIABILITY DATA SUMMARY:**

**Reliability Test Results:**

<b>NCP1271D65R2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 450V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
2	HVTHB	TA=85C, 60%RH, 450V Bias	Test @ 168hrs	3 lots x 80 units	0/240
3	HTOL	TA=125C, 100V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
4	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
5	TC-PC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
6	AC-PC	TA=121C, RH=100%, PSI=15	Test @ 96hrs	3 lots x 80 units	0/240
7	UHAST-PC	TA=130C, RH=85%, PSI=18.8 no Bias	Test @ 1008hrs	3 lots x 80 units	0/240
8	HAST-PC	TA=130C, RH=85%, PSI=18.8 Bias	Test @ 1008hrs	3 lots x 80 units	0/240
9	SAT-PC	Post MSL3 260C	Pre and Post PC	3 lot x 5 units	0/15
<b>NCP1396ADR2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 600V Bias	Test @ 1008hrs	3 lots x 80 units	0/239*
2	HTOL	TA=125C, 600V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
3	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
4	TC-PC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
5	AC-PC	TA=121C, RH=100%, PSI=15	Test @ 96hrs	3 lots x 80 units	0/240
6	UHAST-PC	TA=130C, RH=85%, PSI=18.8 no Bias	Test @ 1008hrs	3 lots x 80 units	0/240
7	HAST-PC	TA=130C, RH=85%, PSI=18.8 Bias	Test @ 1008hrs	3 lots x 80 units	0/240
8	SAT-PC	Post MSL3 260C	Pre and Post PC	3 lot x 5 units	0/15
* (1) EOS failure after 504hrs					
<b>NCP1237AD65R2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 500V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
3	HTOL	TA=125C, 380V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
4	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
5	TC-PC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
<b>SCY991900DWR2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTOL	TA=125C, 600V Bias	Test @ 1008hrs	1 lot x 80 units	0/79*
2	TC-PC	-65C to +150C	Test @ 500 Cycles	1 lot x 80 units	0/80
* (1) EOS failure after 504hrs					
<b>NCP1380BDR2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTOL	TA=125C, 30V Bias	Test @ 1008hrs	1 lot x 80 units	0/80
2	TC-PC	-65C to +150C	Test @ 500 Cycles	1 lot x 80 units	0/80
<b>SCY99068R2G</b>					
#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTOL	TA=125C, 400V Bias	Test @ 1008hrs	1 lot x 80 units	0/80



**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16773**

**NCP1002PG**

#	Test	Test Conditions	Read Points	Sample Size	Results
1	HTBB	TA=125C, 600V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
2	HTOL	TA=125C, 30V Bias	Test @ 1008hrs	3 lots x 80 units	0/240
3	HTSL	TA=150C	Test @ 1008hrs	3 lots x 80 units	0/240
4	TC	-65C to +150C	Test @ 500 Cycles	3 lots x 80 units	0/240
5	AC	TA=121C, RH=100%, PSI=15	Test @ 96hrs	3 lots x 80 units	0/240
6	UHAST	TA=130C, RH=85%, PSI=18.8 no Bias	Test @ 1008hrs	3 lots x 80 units	0/240

**ELECTRICAL CHARACTERISTIC SUMMARY:**

There is no change in the Electrical Performance. Datasheet specifications remain unchanged.

**CHANGED PART IDENTIFICATION:**

Affected products with Date Code WW01-2012 and greater may be sourced from either Gresham or Aizu Wafer Fabrication sites.

**List of affected General Parts:**

- NCP1034DR2G
- NCP1581DR2G
- NCP1031DR2G
- NCP1031MNTXG
- NCP1030DMR2G